

## **Cp E 432: Testing of Computing Systems**

### **ELECTRICAL ENGINEERING**

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for-manufacture, system testability and diagnosability.  
3 Credits

#### **Prerequisites**

- [El E 351: Models and Circuits I](#)
- [El E 385: Advanced Digital Systems](#)
- [El E 386: Advanced Digital Systems Laboratory](#)

#### **Instruction Type(s)**

- Lecture: Lecture for Cp E 432

#### **Subject Areas**

- [Computer Engineering, General](#)

#### **Related Areas**

- [Computer Hardware Engineering](#)

